

STN

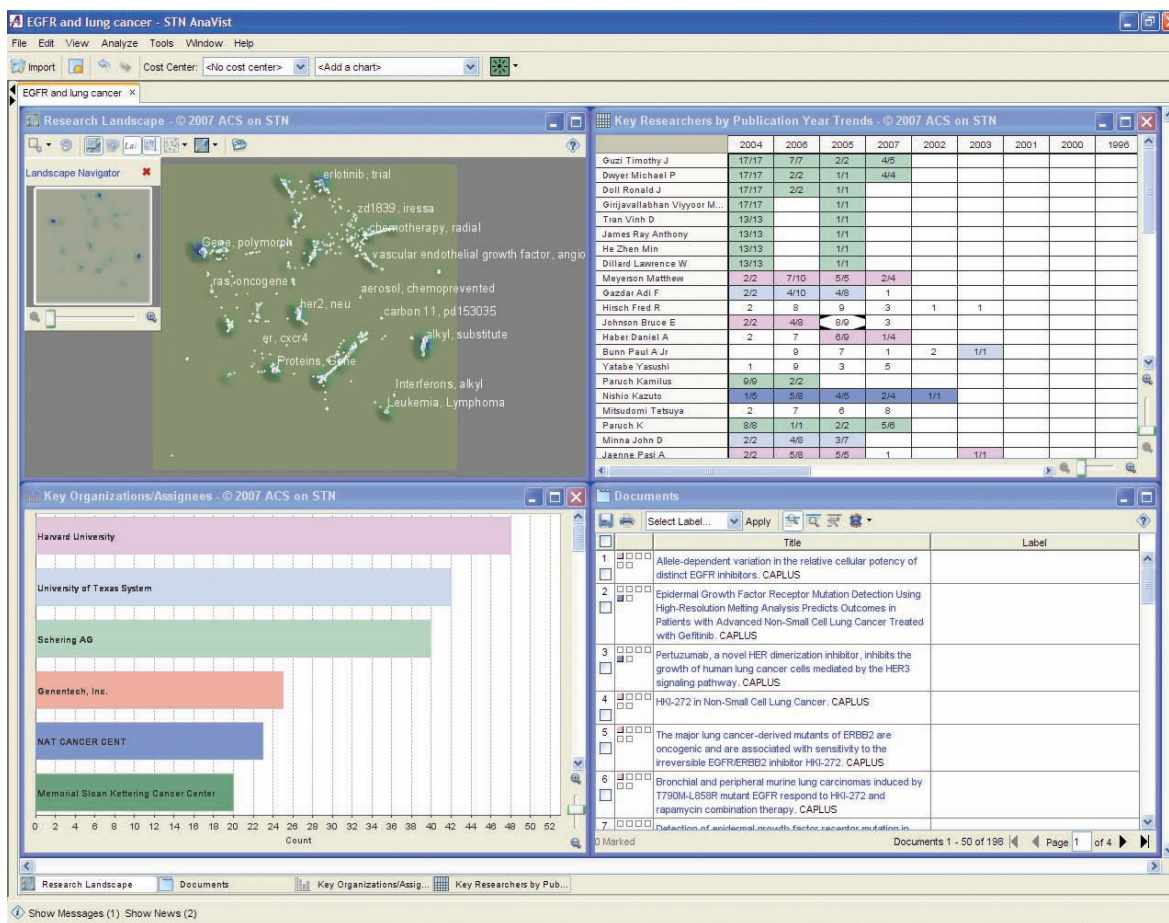


Highlights

- 2** STN[®] AnaVist[™], Version 2.0 – Powerful analysis and visualization software, now better than ever!
- 6** CASM/CAplusSM enhanced with pre-1907 records from *Chemisches Zentralblatt*
- 7** CAS REGISTRYSM enhanced with proton NMR spectra
- 8** (T) – The other proximity operator
- 11** Performing comparative analysis with STN AnaVist, Version 2.0
- 14** 2007 – Year in review

STN[®] ANAVIST[™] Version 2.0

Powerful analysis and visualization software, now better than ever!



Version 2.0 builds on previous versions of STN AnaVist with new and enhanced features, and provides new database content from DWPI. STN AnaVist, Version 2.0, is the only platform that permits simultaneous analysis of CAPLUS and DWPI, with content processed by STN for optimal visualization.

STN[®] AnaVist[™], interactive analysis and visualization software, provides unique insights into trends and patterns in scientific and patent information.

The new STN AnaVist, Version 2.0, not only provides many new and enhanced features for analysis and visualization but also includes content from Derwent World Patents Index[®] (DWPISM).

Current STN[®] customers can download Version 2.0, free of charge, from the STN AnaVist License & Download page at www.cas.org.

STN AnaVist can help you answer complex questions as well as provide information that can be used to *make faster, more informed decisions critical to your business.*

With STN AnaVist, you can:

- ✓ Analyze the patent landscape - determine who, what, where, when, and why
- ✓ Track competitive intelligence - find out what your competitors are doing

- ✓ Discover new applications for existing technology
- ✓ Determine research trends - find whether a particular area of research is on the rise, steady, or declining
- ✓ Support strategic business planning

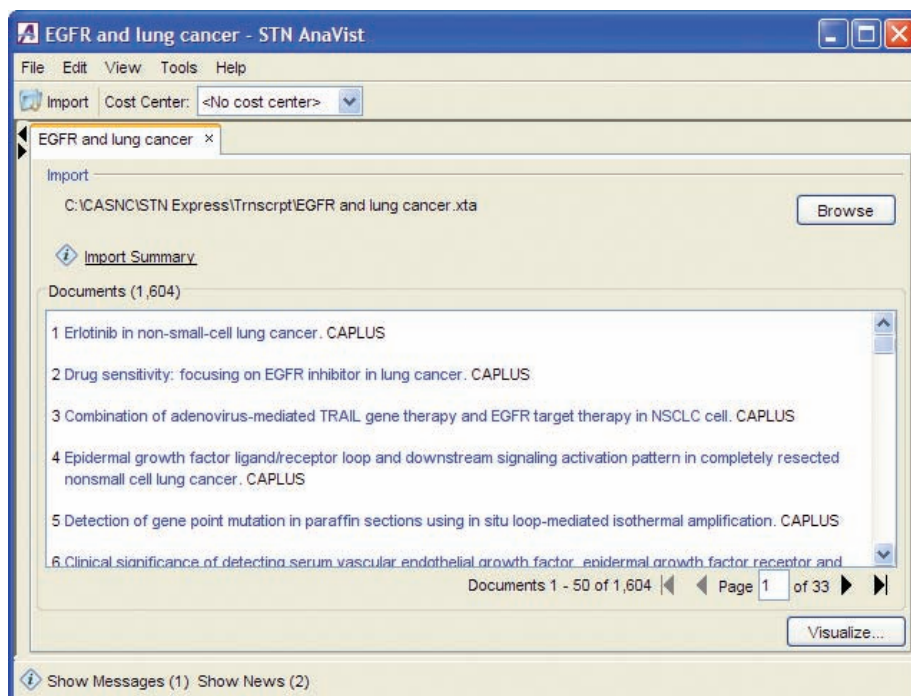
Version 2.0 builds on previous versions of STN AnaVist with new and enhanced features, and provides new database content from DWPI.

See what's new in Version 2.0

To explore the new and enhanced features:

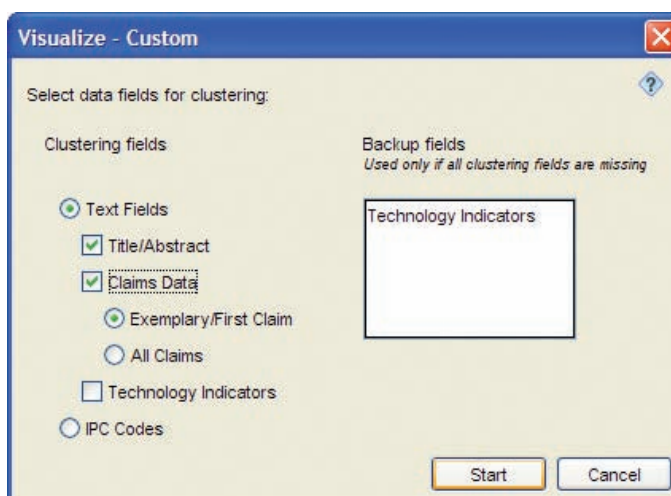
1. Create a document set for visualization with the precise searching capabilities of STN Express, Version 8.2.
2. Import your document set into STN AnaVist, Version 2.0, and click **Visualize...**

Import your document set from STN Express, Version 8.2, and click **Visualize...**



Examine the Research Landscape from your point-of-view!

In previous versions of STN AnaVist, the Title/Abstract data field was your only choice for clustering. With Version 2.0, you can take advantage of new clustering fields, including Technology Indicators, Exemplary/First Claim, All Claims, and International Patent Classification (IPC) Codes. Customize your visualization using any one of the new clustering fields or any of the text fields in combination.



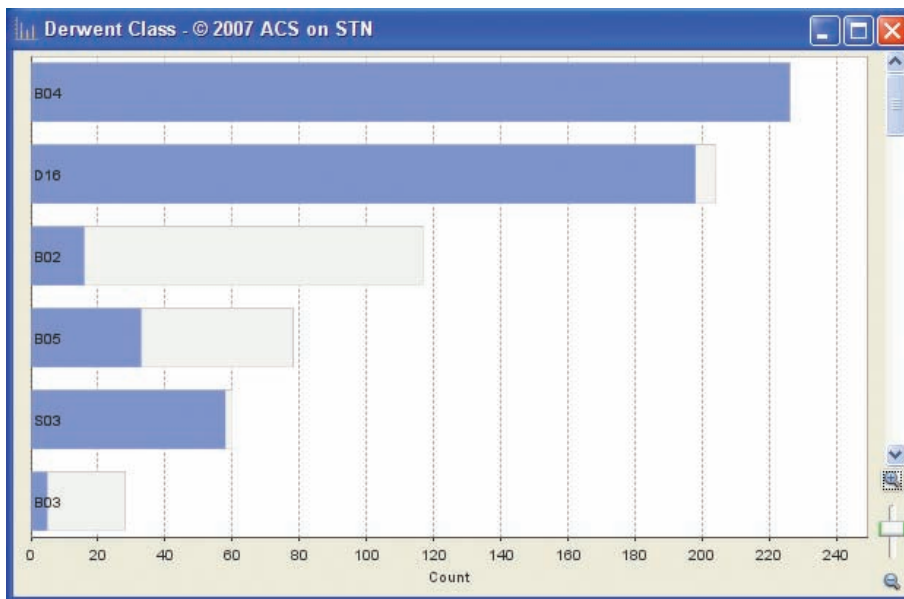
Select a single data field for clustering, or further customize your visualization with a combination of text fields.

NEW

Gain a more complete understanding of your data!

With the addition of DWPI, you can create new bar charts based on Derwent Class, Derwent Manual Codes, and Patent Country Codes/Kind Codes.

Create a bar chart with Derwent Class information from DWPI.

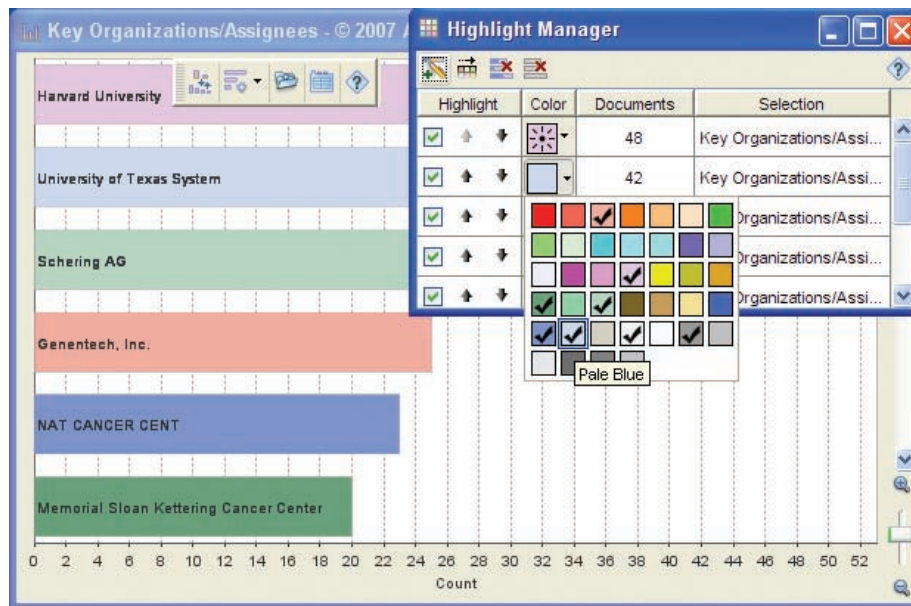


NEW

Perform comparative analysis with ease!

In previous versions of STN AnaVist, when you highlighted a portion of a chart or the Research Landscape, corresponding documents in the other charts would highlight automatically. Highlighting in Version 2.0 works as it did in previous versions, but now you can highlight as many as eight different document sets at once - and select from a palette of 40 colors.

Select colors for document highlighting, up to eight colors at once.

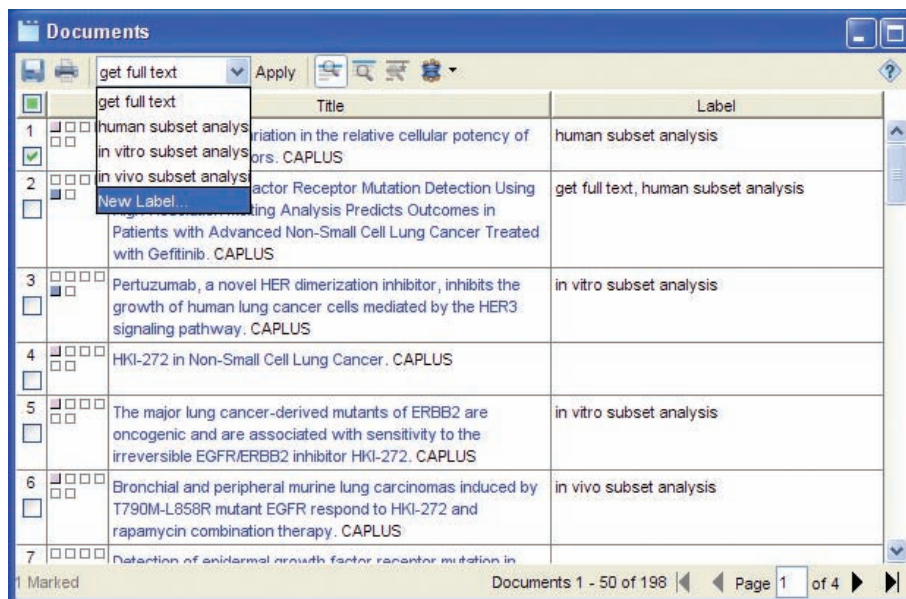


ENHANCED

Manage your documents!

Previously, flagging documents was the only way to label documents in STN AnaVist. With Version 2.0, you can apply custom labels to individual documents or document sets and use the Labels bar chart - created automatically and updated every time you apply labels - to sort your documents by label.

Apply custom labels to individual documents or an entire document set at once.

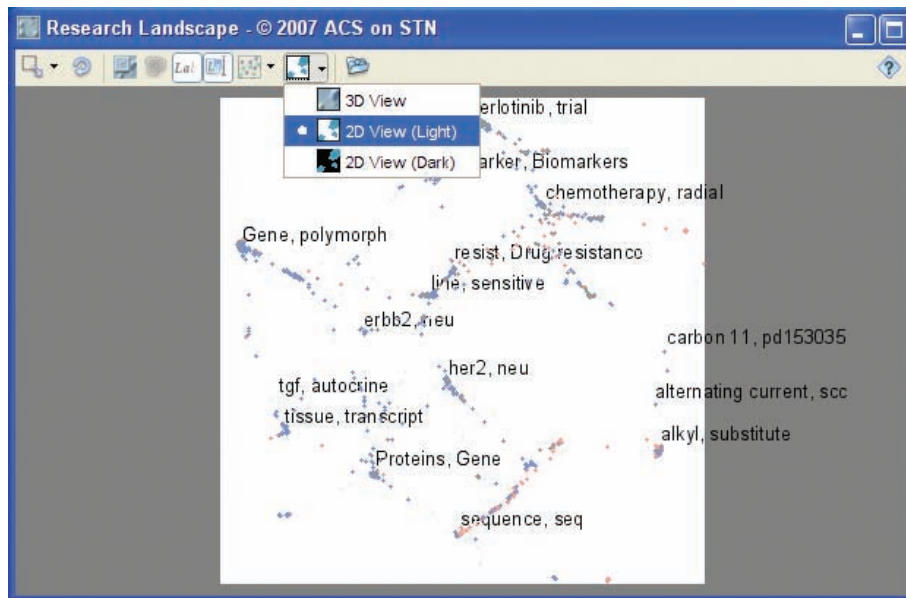


NEW

Pinpoint the research of your competitors and customers!

New 2D display options with white or black backgrounds provide more contrast to show more precisely where your documents lie in the Research Landscape.

Select from three Research Landscape viewing options.



Additional resources

With STN AnaVist, Version 2.0, you can now examine scientific and patent data from all angles. For details about STN AnaVist, including pricing, FAQs, See How It Works, and tutorials, visit the Products & Services and Support web pages for STN AnaVist at www.cas.org.

For additional information on how to use STN AnaVist, refer to the STN AnaVist Avenue article in this and other issues of *STNews*.

Database News includes information on database enhancements released in September-November 2007. For additional information, refer to the Database Summary Sheets available at www.cas.org.

BEILSTEIN

BEILSTEIN updated with new compounds

More than 120,000 new compounds were added to BEILSTEIN. Of the new compounds, approximately 40% are heterocyclic compounds, 20% are polymers, and 20% are biomolecules. Pharmacological and reaction data for many of the new substances have also been added.

CASM/CAplusSM

Enhanced with pre-1907 records from *Chemisches Zentralblatt*

Nearly 18,000 records from 1905-1906 issues of *Chemisches Zentralblatt* have been added to CA/CAplus. A predecessor to *Chemical Abstracts*TM, *Chemisches Zentralblatt* is a German chemical abstracting journal published from 1830-1969.

The new pre-1907 records have been enhanced with English machine translations of Bibliographic (BIB) and Abstract (AB) information. In the Title (TI) and AB fields, translated data is indicated by "machine translation" and "Machine Translation of Descriptors", respectively.

Enhanced with traditional medicine patents from 1985-2005

CAplus has been enhanced with approximately 10,000 traditional medicine patents from 1985-2005. These patents are not represented by new or different kind codes and are not assigned to a CA section.

In the IPC.TAB display format, XC may appear in the CC column (authority issuing the International Patent Classification code). XC indicates that the patent has been examined by CAS, but it is not part of the reclassification supplied by the European Patent Office (EPO). The presence of XC provides an additional way to search IPC codes.

EMBASE, EMBAL, and LEMBASE

Reloaded with enhancements

Excerpta Medica (EMBASE), EMBASE Alert (EMBAL), and the EMBASE learning database (LEMBASE) have been reloaded with a number of enhancements:

- Records now include 10- and 13-digit ISBNs when available
- Accession Numbers (AN) now include the 4-digit year throughout the database

The following fields have been removed:

- Document Number (DN)
- Meeting Date (MD)
- Meeting Year (MY)

EMBAL also includes the following enhancements:

- Simultaneous left and right truncation (SLART) in the Abstract (AB), Title (TI), and Basic Index (BI) fields
- Separately searchable AB field

For additional information on the reloads, enter HELP RLOAD at an arrow prompt (=>) in EMBASE, EMBAL, and LEMBASE.

FORIS

Renamed SOFIS on STN[®]

Forschung Informationssystem Sozialwissenschaften (FORIS) has been renamed Sozialwissenschaftliches Forschungsinformationssystem (SOFIS). On STN, FORIS can be used as an alias of SOFIS.

SOFIS (Social Science Information System) includes information on more than 45,000 theoretical and empirical research projects in the social sciences from German-speaking countries during the last 10 years. The database offers detailed descriptions of the contents (abstracts), research methods, and data collection procedures, as well as bibliographic information on research reports and publications.

ICSD

Reloaded with enhancements

The Inorganic Crystal Structure Database (ICSD) has been reloaded and now includes more than 100,000 records. In addition, ICSD has been enhanced with a Crystallographic Information File (CIF) display format and download option for seamless integration of ICSD data into third-party applications.

ICSD is a comprehensive collection of crystallographic and bibliographic data on inorganic crystal structures. Coverage includes crystalline inorganic materials that have been structurally determined from 1913 to the present. ICSD is updated twice per year.

An ICSD information sheet is available from FIZ Karlsruhe at www.stn-international.de/archive/stn_brochures/ICSD_Flyer.pdf.

INPADOCDB

Enhanced with monthly SDI frequency

Current-awareness alert (SDI) frequency in the International Patent Documentation Database (INPADOCDB) may now be set to weekly (default) or monthly.

Family SDI display formats are valid for the current update only and should not be used for monthly SDIs.

For details on pricing, enter HELP COST at an arrow prompt (=>).

LINPADOCDB

Now available on STN®

The International Patent Documentation Database (INPADOCDB) learning database (LINPADOCDB) has been added to STN. Included in the database are approximately 310,000 records with bibliographic data, abstracts, citations, and patent family and legal status information derived from INPADOCDB.

As a static learning database, LINPADOCDB is not updated and current-awareness alerts (SDIs) are not available.

Enter HELP COST at an arrow prompt (=>) for details on LINPADOCDB pricing.

REGISTRY

Enhanced with additional experimental spectral property data

More than 85,000 proton NMR spectra for nearly 84,000 substances have been added to CAS REGISTRYSM.

The Field Availability (FA) search field has been updated with:

- Hydrogen-1 NMR Spectra
- Proton NMR Spectra

Substances with proton NMR spectra are also retrieved with the existing FA terms:

- Spectra
- NMR Spectra

In addition, two new display formats have been added to display spectral images:

- SPEC.H1NMR
- SPEC.PROTONNMR

The new formats are aliases of each other. Proton NMR spectra are also displayed in the spectra (SPEC) display format.

WPIX

Enhanced with XML display format

An XML display format has been added to the Derwent World Patents Index[®] (DWPISM with Extension Abstracts) subscriber database (WPIX). The XML format is identical to the format distributed by Thomson Scientific and can be validated against the corresponding Thomson Scientific Document Type Description (DTD). For a copy of the DTD, contact Thomson Scientific Global Customer Support at <http://scientific.thomson.com/support/>.

To obtain the XML format for a retrieved document in WPIX, enter DISPLAY XMLDOC at an arrow prompt (=>). The display includes a hyperlink that provides access to a compressed (zipped) file of the record in XML format. When the hyperlink is clicked, a one-time display fee is incurred. The link may be accessed multiple times at no additional charge for 90 days.

Enter HELP COST at an arrow prompt (=>) for details on pricing.

STN[®]

(T) – The other proximity operator

STN's proximity operators can help you generate a comprehensive set of records relevant to your topic of interest, while eliminating extraneous answers. Placed between terms in your query, proximity operators are effective tools to limit, widen, or otherwise define your search. You can use proximity operators not only to require that two terms appear near each other but also to require that two fragments appear within the same term.

Overview of proximity operators and their standard usage

In addition to the Boolean search operators AND, OR, and NOT, STN offers proximity operators with which you can indicate, with even greater precision, how closely terms and concepts must appear within a record.

Although proximity operators can have additional, specialized applications in some databases, the inverted triangle at the far right illustrates the overall relationship between the operators and their definitions in most databases. As you move toward the tip of the triangle, the operators require tighter linkage between the concepts or terms in your query.

For this discussion, a term is defined as "space-to-space" and a fragment can be any 4-letter portion of a term. However, in two cases described later in this

article, "fragment" has a more specialized definition.

The (T) proximity operator

Linking two fragments in a search query with (T) requires that they appear within a *single term* in the retrieved record(s). This intra-term association differentiates (T) from all other proximity operators, which specify inter-term associations.

Since two fragments cannot simultaneously occur at the beginning of a single term, you must use left truncation to indicate the fragment(s) that may be found embedded in or at the end of a term. Therefore, the (T) operator can typically only be used when conducting text searches in fields that permit simultaneous left and right truncation (SLART).

Answers retrieved with (T)

The search example at the right returns records with both of the fragments *anti* and *allerg* in a single term in the Basic Index.

This search yields an answer set in which records contain terms such as *antiallergic*...

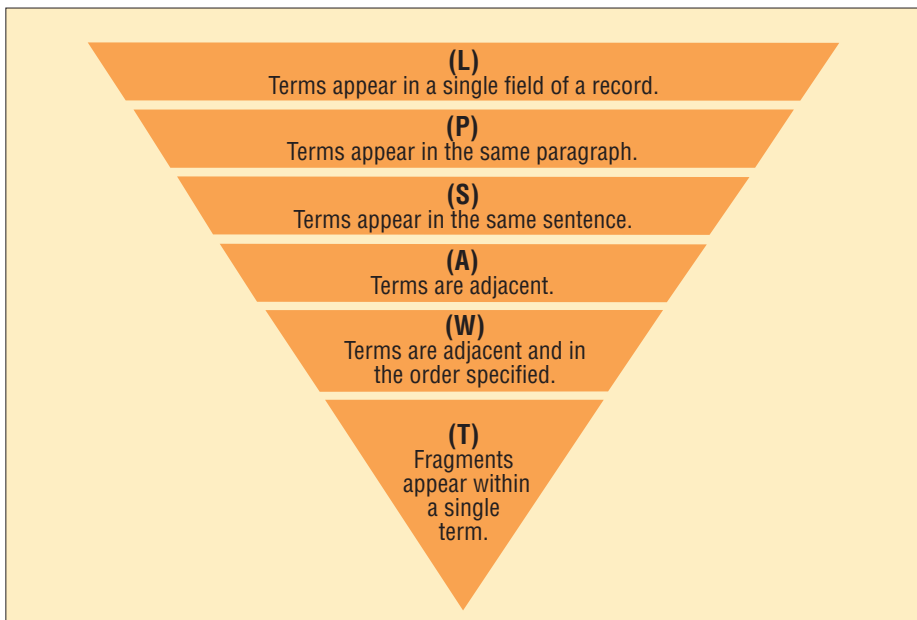
...as well as terms in which *anti* and *allerg* are not adjacent but are still within a single term, such as *antiimmunoallergic*.

```
=> FIL WPINDEX
=> S ?ANTI? (T) ?ALLERG?
      1171169 ?ANTI?
      35080 ?ALLERG?
L6    16477 ?ANTI? (T) ?ALLERG?
```

```
=> D KWIC 1-10
L6    ANSWER 2 OF 16477 WPINDEX COPYRIGHT 2007    THE THOMSON CORP
      on STN
ACTV ACTIVITY - Antiasthmatic; Antiallergic; Antiinflammatory...
```

```
L6    ANSWER 14651 OF 16477 WPINDEX COPYRIGHT 2007    THE THOMSON CORP
      on STN
ACTV ACTIVITY - Antiinflammatory; antiimmunoallergic;
      keratinocyte antiproliferation agent; dermatological;
      antirheumatic...
```

The (T) operator is one of many STN tools that can help you increase the precision of your search queries.



It is possible that the fragments specified in the search query overlap in the retrieved record.

```
=> FILE CAPLUS
=> S ?PYRO? (T) ?OXYL?
      354799 ?PYRO?
      1065632 ?OXYL?
L1      1996 ?PYRO? (T) ?OXYL?
```

```
=> D L1 2 AB
L1 ANSWER 2 OF 1996 CAPLUS COPYRIGHT 2007 ACS on STN
AB ...connected with the anti-F1 antibody of Yersinia pestis to
  pyroxylin membrane and assembled...
```

Or, they may appear in the reverse order.

```
=> D L1 14 AB
L1 ANSWER 14 OF 1996 CAPLUS COPYRIGHT 2007 ACS on STN
AB ...conversion of Pheid a to a precursor of pyropheophorbide
  (PyroPheid), C-132-carboxylPyroPheid a, by demethylation,...
```

Using (T) to find chemical substances

In CHEMSAFE and DETHERM, the (T) operator performs a specialized function. It can be used to define a search for chemical substances in the Element Count (/ELC) or Element Symbol (/ELS) field. You can use (T) to limit search results to records in which two elements are part of the same molecular formula. Further, you can specify the number of those elements in the molecular formula.

In the search at the right, the query requires that 2 silver atoms and 3 oxygen atoms are present in a single molecular formula.

```
=> FIL DETHERM
=> S 2/AG (T) 3/O
      177 2/AG
      36135 3/O
L2      9 2/AG (T) 3/O

=> D HIT
L2 ANSWER 1 OF 9 DETHERM COPYRIGHT 2007 DECHEMA/FIZC on STN
Substance (1) of (1):
Chemical Name (CN): Silver bromide metaphosphate (AgBr0.55(PO3)0.45)
Molecular Formula (MF): Ag2 Br O3 P
CAS Reg. Number (RN): 172850-19-0
```

Using (T) in patent databases

The (T) operator also has a specialized use in the following patent databases: DPCI, FRANCEPAT, KOREAPAT, INPADOCDB, and the Derwent World Patents Index® (DWPISM) databases. In addition to finding fragments or elements in a single “term” in a record, (T) can require that the fragments belong to a single patent classification or structure identifier. For example, each IPC Main Group (/MGR) or Subgroup (/SGR) can be linked to the corresponding subclass entries.

```
=> FIL WPINDEX
=> S B31B/ICM (T) 19-41/MGR
      852 B31B/ICM
      5489292 19-41/MGR
L2      213 B31B/ICM (T) 19-41/MGR

=> D HIT
L2 ANSWER 1 OF 213 WPINDEX COPYRIGHT 2007 THE THOMSON CORP on STN
IC ICM B31B019-00
ICS B31B019-62; B31B027-00
```

Too many terms

Using the (T) operator with common word fragments occasionally retrieves so many answers that system limits are exceeded.

In such instances, you may consider imposing additional restrictions on your search, or lengthening at least one of the fragments. In this example, adding the letter *O* to the end of *AMIN* keeps the search results within system limits.

```
=> FIL CAPLUS
=> S ?OXYL? (T) ?AMIN?
TERM 'AMIN?' EXCEEDED TRUNCATION LIMITS - SEARCH ENDED You have
entered a truncated stem which occurs in too many terms. Make the
stem longer and try again. For example, if your original term
was 'degr?' to search for variations and the abbreviation for
'degradation', you could replace it with the expression '(degrdn OR
degrad?)'. If your search term was numeric, e.g., 'C>5', reduce the
size of the range.
```

```
=> S ?OXYL? (T) ?AMINO?
      1068940 ?OXYL?
      1864028 ?AMINO?
L1      16923 ?OXYL? (T) ?AMINO?
```

Conclusion

The (T) operator has the unique ability to require that multiple fragments appear in a single term in the retrieved records. In most databases, a fragment is any 4-letter portion of a term. In a limited number of databases, the definition of “fragment” can be extended to include elements within a molecular formula or even components of patent data.

The (T) operator is one of many STN tools that can help you increase the precision of your search queries.

Additional resources

For more information on using (T), log on to a particular database and enter HELP (T) at an arrow prompt (=>). If no help message displays, (T) can be used in fields with SLART. If you are in a database in which (T) can be used to find chemical substances or patent data, the help message gives a brief description and search example.

To learn more about search term proximity operators, consult the following topics at www.cas.org:

- STN Documentation
- STN Databases with SLART

Performing comparative analysis with Version 2.0



This article illustrates how to compare Key Organizations/Assignees based on data from the Derwent World Patents Index® (DWPISM), now available in STN® AnaVist™, Version 2.0. The following topics are covered:

- Using the new Highlight Manager
- Creating charts with Derwent Class and Derwent Manual Codes data
- Comparing Key Organizations/Assignees based on DWPI data

Using the new Highlight Manager

With the new Highlight Manager in STN AnaVist, you can compare as many as eight document sets at once. Simply pick the highlight color for each set from a palette of 40 colors.

- **To create your first highlight set**, click the Highlight Color Selector and select **Highlight Manager** from the drop-down menu.



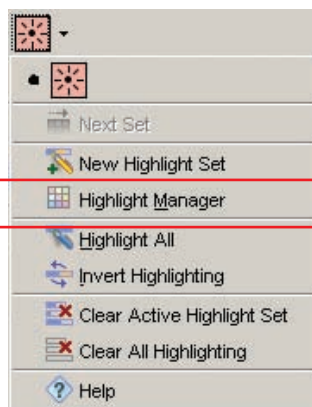
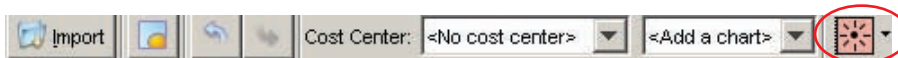
Within the Highlight Manager, each row corresponds to an individual highlight set while columns display information about each set. Your newly created highlight set displays on the first row with the default color.

The two sets shown in the last two rows are present at all times. The “overlap” set represents documents shared by more than one highlight set (see additional information below). The “unhighlighted” set represents documents that are not associated with any highlight set.

- **To add another highlight set**, click the **New Highlight Set** button located on the Highlight Manager toolbar. The second highlight set displays in the list and is assigned a default color.



With the new highlighting features in STN AnaVist, Version 2.0, comparative analysis is now easier than ever.



First highlight set

Highlight	Color	Documents	Selection
<input checked="" type="checkbox"/>		0	
<input type="checkbox"/>		0	Overlap between highlight s...
<input type="checkbox"/>		722	Unhighlighted

Second highlight set

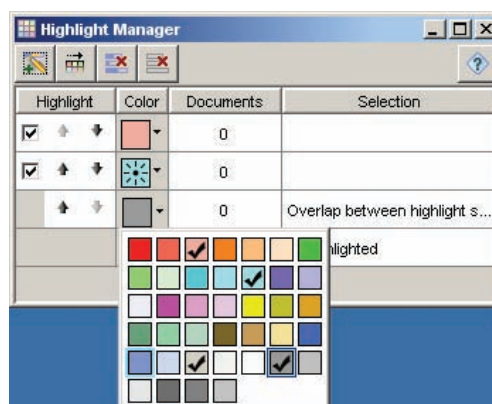
Highlight	Color	Documents	Selection
<input checked="" type="checkbox"/>		0	
<input checked="" type="checkbox"/>		0	
<input type="checkbox"/>		0	Overlap between highlight s...
<input type="checkbox"/>		722	Unhighlighted

With the new Highlight Manager in STN AnaVist, you can compare as many as eight document sets at once.

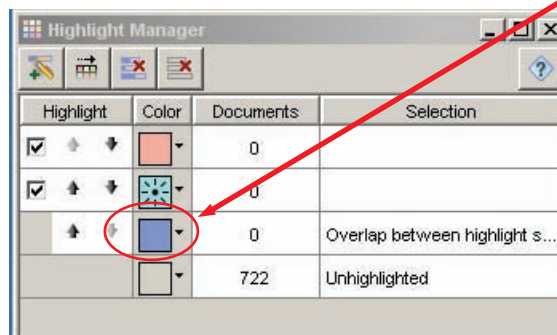
- **To change the color of a highlight set**, click the appropriate cell in the Color column. Select your color preference from the color palette.

Notice that you can also change the color for “overlap” and “unhighlighted” documents.

The Highlight Manager now shows the default colors for two highlight sets and a new color for overlapping documents.

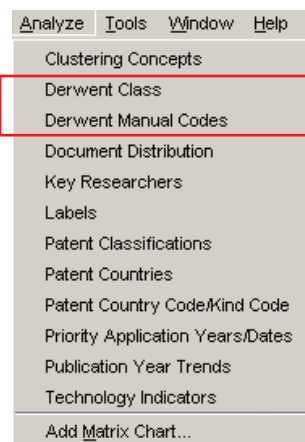


New highlight color





Creating charts with Derwent Class and Derwent Manual Codes data

To create charts with DWPI data, use the **Analyze** menu or the **<Add a chart>** drop-down menu to select **Derwent Class** or **Derwent Manual Codes**.



Comparing Key Organization/Assignees based on DWPI data

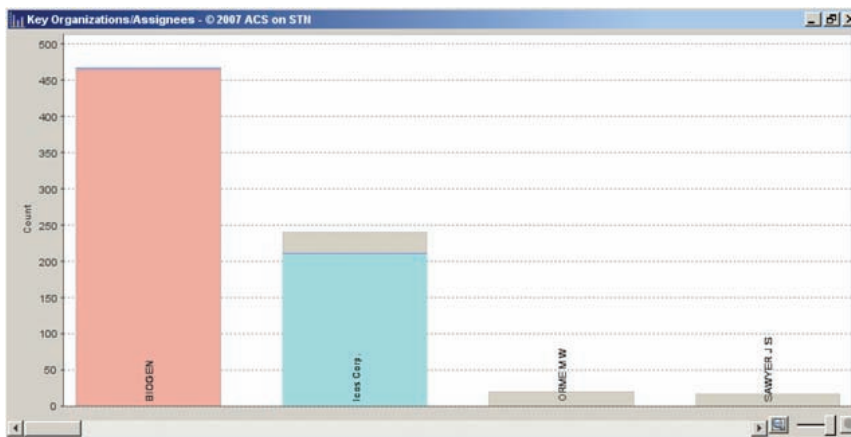
Now you can use the colors selected with the Highlight Manager to compare document data. In this example, Key Organizations/Assignees are compared by using charts for Derwent Class and Derwent Manual Codes.

1. Check the toolbar to see which color is active in the Highlight Color Selector. 
2. On the Key Organizations/Assignee chart, click the bar for the first patent assignee of interest.
3. Select the second color from the Highlight Color Selector. 
4. Click the bar for the second patent assignee of interest.

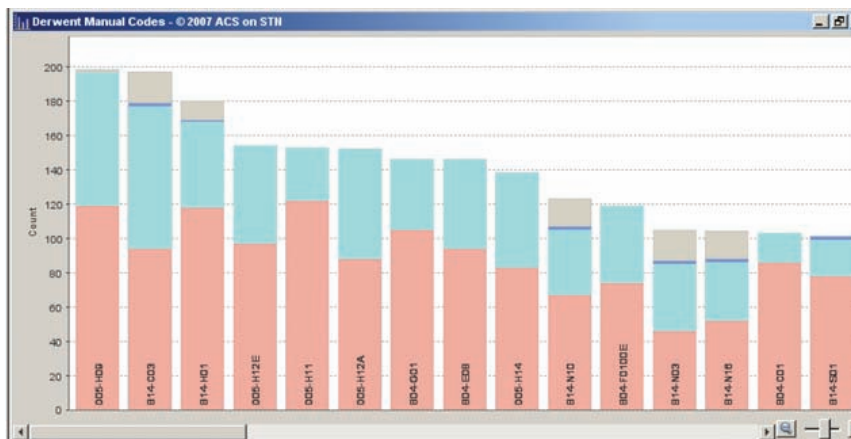
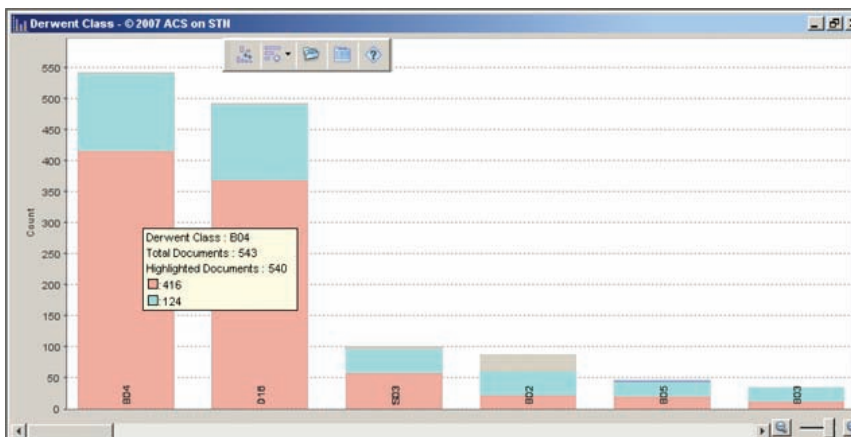
Documents for the two patent assignees are now highlighted in two different colors.

In the Derwent Class and Derwent Manual Codes charts, you can compare documents associated with the two patent assignees.

Highlight colors within the bars indicate the number of documents per patent assignee, as well as any documents that overlap between the highlight sets. Hover over each bar to view details.



Derwent Class and Derwent Manual Codes charts showing highlight sets for two patent assignees.



Additional resources

This article discusses just a few of the new features available in STN AnaVist, Version 2.0. To learn about other new features, see the Feature article in this issue of *STNews*.

For additional information about STN AnaVist, visit the STN AnaVist Products & Services and Support pages at www.cas.org.

2007 - Year in review

This year brought many enhancements to STN[®], including a new patent evaluation tool, important improvements to established interfaces, significant additions and updates to database content, new patent-related databases, and numerous training opportunities.

This article summarizes notable STN enhancements covered by *STNews* in 2007. Issue and page references for all 2007 news may be found in *STNews: An index to the 2007 issues*, included with this issue of *STNews* and available at www.cas.org.

Interfaces

June

STN[®] Viewer[™] – a powerful workflow productivity tool for patent information users

STN Viewer is a new web-based tool designed to aid in the patent evaluation process. It provides an efficient way for patent information professionals to communicate findings to intellectual property professionals and others interested in full-text patent information.

STN Viewer is the only patent evaluation tool integrated with the high-quality full-text patent databases on STN and the precise searching capabilities and post-processing features of STN Express[®].

Additional information is available in:

- Take Note
Issue No. 2, page 20
- Feature
STN Viewer – A powerful workflow productivity tool for patent information users
Issue No. 3, pages 2-4
- STN Expressway
Creating full-text patent answer sets for evaluation with STN Viewer
Issue No. 3, pages 12-14
- STN Viewpoint
Using the highlighting feature to speed the patent evaluation process
Issue No. 3, pages 15-17

June

STN Express, Version 8.2 – software now free to all STN users

STN Express, Version 8.2, is available to all STN users as a free upgrade to any previous version of the software. Version 8.2 also provides new functionality to create answer sets for STN Viewer and STN[®] AnaVist[™], and improves compatibility with Derwent World Patents Index[®] (DWPISM) and INPADOCDB.

Additional information is available in:

- Take Note
Issue No. 2, page 21
- STN Expressway
Creating full-text patent answer sets for evaluation with STN Viewer
Issue No. 3, pages 12-14

September

STN AnaVist, Version 2.0 – now available with Derwent World Patents Index

STN AnaVist, Version 2.0, not only provides many new and enhanced features for analysis and visualization but also includes content from DWPI. Enhancements in Version 2.0 include new data fields for clustering, a variety of new bar charts, new document highlighting and labeling features, and new 2D displays of the Research Landscape.

STN AnaVist, Version 2.0, is the only platform that permits analysis of both CAplusSM and DWPI, with content processed by STN for optimal visualization.

Additional information is available in:

- Take Note
Issue No. 3, page 18
- Feature
Powerful analysis and visualization software, now better than ever!
Issue No. 4, pages 2-5
- STN AnaVist Avenue
Performing comparative analysis with Version 2.0
Issue No. 4, pages 11-13

2007 - Year in review

Databases

January

CAS REGISTRYSM – new CA index name rules applied to previously registered substances

In 2006, CAS began the transition from 9CI (9th Collective Index) index nomenclature rules to new CA index nomenclature rules - the first major rule changes for CA index names since 9CI rules were adopted in 1972. All newly registered substances in REGISTRY are assigned a CA index name in compliance with the new rules, and updates to CA index names of previously registered substances also began in 2007.

Details are available in:

- Ask REGgie
New CA index name rules in 2007
Issue No. 1, pages 6-8

April

INPADOCDB – replaces INPADOC

Data from the INPADOC(PRS) and DOCDB harmonization project of the European Patent Office (EPO) is available in the new International Patent Documentation Database (INPADOCDB), replacing INPADOC on STN.

As the world's largest repository of bibliographic patent data, INPADOCDB covers 80 patent-issuing organizations and includes records from certain organizations dating back to the 1800s. INPADOCDB also includes INPADOC legal status data from 48 organizations. In total, INPADOCDB includes 51 million records and is updated weekly with 70,000-100,000 additional new records.

Additional information is available in:

- Database News
Issue No. 1, page 4
Issue No. 2, page 6
- Patent Interchange
INPADOCDB – The enhanced INPADOC database
Issue No. 2, pages 15-17

July

USGENE[®] – a new sequence patent database

The United States Patent and Trademark Office (USPTO) Genetic Sequence Database (USGENE), produced by SequenceBase Corporation, is available on STN.

USGENE brings together USPTO sequence data with key elements of bibliographic and full-text data to provide a unified platform in which patent searchers can combine sequence data, date, and patent claims text searching. Coverage includes all available peptide and nucleic acid sequences from published applications and issued patents of the USPTO from 1982 to the present.

Details are available in:

- Database News
Issue No. 3, page 6

August

USPATOLD – a new full-text patent database

U.S. Patents Pre-1976 (USPATOLD), now available on STN, includes more than 3.5 million records and covers the full text of patents issued from the United States Patent and Trademark Office (USPTO) from 1790-1975.

USPATOLD records represent original U.S. patent documents converted into electronic form through an optical character recognition (OCR) process. Approximately 500,000 USPATOLD records, representing patents also covered by CAPLUS, were supplemented with CAS data.

Details are available in:

- Database News
Issue No. 3, page 7

Many additional updates to STN databases were implemented during 2007. For a full recap, review the Database News articles in each issue of *STNews*.

2007 - Year in review

Training

CAS e-Seminars are web-based seminars that bring professional training to your desktop. In 2007, the following e-Seminars were offered:

- Citation Searching
- Improving Searches by Including Patent Classification Codes
- Introduction to STN AnaVist, Version 2.0
- Keeping Your Current Awareness Alerts Current
- Post-Processing Tools in STN Express with *Discover!*
- Revisiting the Basics of Structure Searching
- Searching for Patent Prior Art Evidence of Obviousness
- STN Case Study - Adhesives
- STN Case Study - Approaches to Finding Biotech Prior Art
- STN Case Study - Diagnostics and Instrumentation
- STN Case Study - Finding Petroleum/Petrochemical Information
- STN Continuing Education - Habits for Increasing Confidence in Search Results
- STN Continuing Education - What's New?
- STN Viewer - A New Workflow Productivity Tool for Patent Information
- Text-Based Techniques for Engineering Information
- The Secret Life of CAPlus
- Using Scripts and STN Tools to Make Searching Easier
- Using STN AnaVist, Version 2.0

To view a recording, visit <https://casevents.webex.com>.

For the latest information about STN interfaces, databases, and training, visit www.cas.org.



Now is the time to upgrade to STN Express®, Version 8.2

If you haven't upgraded your STN Express software within the past year, now is the time! Here are the key reasons why:

- The software is now free to all STN login ID holders, so why not take advantage of the added benefits.
- With the latest version, you get the most up-to-date features and fixes to reported software problems.
- Take advantage of all the features in the latest STN product releases, including STN® AnaVist™, Version 2.0, and STN® Viewer™.

To download your free version of STN Express, Version 8.2, visit the STN Express License & Download page at www.cas.org.

Order your STN® Database Catalog

NEW

Printed copies of the STN Database Catalog will be available in early 2008. The catalog provides:

- Descriptions of STN databases
- Listings of STN database producers
- A comparison chart for STN databases
- Listings of STN database clusters



Are you interested in receiving a free copy? Please complete and return the postcard enclosed with this issue of *STNNews*.

Alternatively, you can e-mail your request to help@cas.org. Be sure to include your name and complete address with your request. Please also indicate if you would like to receive information about additional CAS products and services.

STN[®] Derwent Indian patent publication number format enhanced

Patent publication numbers assigned in India (IN) are identical among the four regional patent offices, e.g., the first Indian patent publication number issued from each office in 2007 is IN 2007-1. To ensure that publication numbers from each of the regional patent offices are unique, STN[®] and Derwent patent publication number formats have been enhanced to distinguish patent applications by type and regional office.

As described below, there are a number of differences between the enhanced STN and Derwent Indian patent publication number formats. However, the differences do not affect database crossover between CPlusSM and Derwent World Patents Index[®] (DWPISM).

STN format for Indian patent publication numbers

The new STN format for Indian patents was implemented in January 2007. Patent publication numbers now include one of eight codes to identify application type and filing office, placed in front of the five-digit publication serial number. The codes include:

- DE – national application filed in Delhi
- DN – PCT application filed in Delhi
- KO – national application filed in Kolkata
- KN – PCT application filed in Kolkata
- MU – national application filed in Mumbai
- MN – PCT application filed in Mumbai
- CH – national application filed in Chennai
- CN – PCT application filed in Chennai

Derwent format for Indian patent publication numbers

With the new Derwent format for Indian patents, publication numbers in the index are now appended with one of eight patent kind codes to identify application type and filing office [in place of World Intellectual Property Office (WIPO) kind codes for Indian patent publications]. The patent kind codes include:

- I1 – national application filed in Delhi
- P1 – PCT application filed in Delhi
- I2 – national application filed in Kolkata
- P2 – PCT application filed in Kolkata
- I3 – national application filed in Mumbai
- P3 – PCT application filed in Mumbai
- I4 – national application filed in Chennai
- P4 – PCT application filed in Chennai

DWPI coverage of Indian patent applications and granted patents published from December 4, 2004, to the present began when the new Indian patent legislation first took effect. Coverage includes pre-grant (18 month) applications and national phase PCT applications issued by the four regional patent offices in India.

Comparison of STN and Derwent formats for Search, Expand, and Display

This table provides a summary of possible patent publication number formats for granted Indian patents:

STN Search and Expand	STN Display	Derwent Search and Expand	Derwent Display
INYYYYDEnnnnn	IN YYYYDEnnnnn	INYYYYnnnnn I1	IN---YYYYnnnnn
INYYYYDNnnnnn	IN YYYYDNnnnnn	INYYYYnnnnn P1	IN---YYYYnnnnn
INYYYYKOnnnnn	IN YYYYKOnnnnn	INYYYYnnnnn I2	IN---YYYYnnnnn
INYYYYKNnnnnn	IN YYYYKNnnnnn	INYYYYnnnnn P2	IN---YYYYnnnnn
INYYYYMUnnnnn	IN YYYYMUnnnnn	INYYYYnnnnn I3	IN---YYYYnnnnn
INYYYYMNnnnnn	IN YYYYMNnnnnn	INYYYYnnnnn P3	IN---YYYYnnnnn
INYYYYCHnnnnn	IN YYYYCHnnnnn	INYYYYnnnnn I4	IN---YYYYnnnnn
INYYYYCNnnnnn	IN YYYYCNnnnnn	INYYYYnnnnn P4	IN---YYYYnnnnn

(nnnnn = serial number with leading zeros to five digits)

To display the Derwent patent publication number format, enter SET PATENT DERWENT at an arrow prompt (=>). Enter SET PATENT STN to return to the default STN patent publication number format.

STNews

STNews is written and produced cooperatively by Chemical Abstracts Service, FIZ Karlsruhe, and JAICI and printed in three separate editions.

Staff, North American Edition:

Editor: Peter Carlton

FIZ Karlsruhe

Dr. Gerhard Herlan

JAICI

Keiko Hayakawa

Contributing Editors:

Elizabeth Haines
Ramona Joseph
Alena Miller

Design/Production:

Pat Farnlacher
Nadine Mosley

For the North American Edition ©2007 American Chemical Society. Quoting or republishing of material from STNews is encouraged provided that acknowledgement is made of STNews as the source. CAS requests that a copy of the reproduced material be sent to CAS Customer Care, P.O. Box 3012, Columbus, OH 43210-0012 U.S.A. Please send all address changes to CAS, P.O. Box 3012, Columbus, OH 43210-0012 U.S.A. E-mail us at help@cas.org.

STNews binders available



Want a binder for your 2007 issues? CAS has *STNews* binders available.

To request your free binder, contact CAS Customer Care at help@cas.org. Be sure to include your name and complete address with your request.

STNewsline – did you sign up?

STNewsline, our electronic newsletter, is published every month. Are you receiving it?

You are not automatically signed up to receive STNewsline just because you receive *STNews*. We need your e-mail address to send it to you.

To receive the latest news about STN by e-mail, visit www.cas.org.

Or, complete this form and fax it to: *STNews* Editor, 614-447-3837.

YES! Sign me up to receive STNewsline:

NAME

E-MAIL ADDRESS

ORGANIZATION

COUNTRY

2008 CAS Trade Shows

For the most current list of CAS trade shows, visit www.cas.org.

ALISE

Philadelphia, Pennsylvania
January 8-11

Norwegian Organic Chemistry Meeting

Norway
January 10-13

Israel Analytical Chemical Society

Tel Aviv, Israel
January 22-23

1st International Conference on Drug Design & Discovery

Dubai, UAE
February 3-6

Israel Chemical Society Meeting

Jerusalem, Israel
February 4-5

VALA (Victorian Association for Library Automation Conference)

Melbourne, Australia
February 5-7

AUTM (Association of University Technology Managers)

San Diego, California
February 28-March 1

PITTCON

New Orleans, Louisiana
March 2-7

NC3 (Netherlands Catalysis and Chemistry Conference)

Noordwijkerhout, Netherlands
March 3-5

Chemiedozententagung (Chemistry Instructors Conference)

Kaiserslautern, Germany
March 30-April 2

Analytica 2008 (Analysis, Laboratory Technology and Biotechnology)

Munich, Germany
April 1-4

ACS National Spring Meeting

New Orleans, Louisiana
April 6-10

SLA Arab Section Meeting

Qatar
April 15-17

World Congress on Industrial Biotechnology and Bioprocessing

Chicago, Illinois
April 27-30

30th Symposium on Biotechnology for Fuels and Chemicals

New Orleans, Louisiana
May 4-7

ERBI Conference

Cambridge, UK
May 7-9

FAME

Kissimmee, Florida
May 8-10

PIUG Annual Conference

Crystal City, Virginia
May 17-22

Biomed Research Equipment & Supplies Exhibit

Frederick, Maryland
May 14-15

Canadian Chemical Society Meeting

Edmonton, Alberta
May 24-25

Renewable Resources and Biorefineries Conference

Rotterdam, Netherlands
June 1-4

PATINFO 2008

Ilmenau, Germany
June 12-13

IExpo (Digital Information Exposition)

Paris, France
June 14

SLA Annual Conference

Seattle, Washington
June 15-18

BIO (Biotechnology Industry Organization Conference)

San Diego, California
June 17-20

Green Chemistry and Engineering Conference

Washington, DC
June 23-27

CPhI China (Convention on Pharmaceutical Ingredients)

Shanghai, China
June 24-26

2008 CAS e-Seminars

1/10	9:00-10:00 a.m.	STN® Case Study – Approaches for Finding Biotech Prior Art (rebroadcast)
1/29	1:00-2:00 p.m.	Ready, SET, Go!
2/14	9:00-10:00 a.m.	Ready, SET, Go! (rebroadcast)
2/25	1:00-2:00 p.m.	Creating Superior Document Sets for STN® AnaVist™, Version 2.0
3/13	9:00-10:00 a.m.	Creating Superior Document Sets for STN AnaVist, Version 2.0 (rebroadcast)
3/25	1:00-2:00 p.m.	Structure Drawing in STN
4/10	9:00-10:00 a.m.	Structure Drawing in STN (rebroadcast)
4/29	1:00-2:00 p.m.	Multifile Searching for Scientific Information
5/8	9:00-10:00 a.m.	Multifile Searching for Scientific Information (rebroadcast)
5/27	1:00-2:00 p.m.	Searching Formulations on STN
6/12	9:00-10:00 a.m.	Searching Formulations on STN (rebroadcast)
6/24	1:00-2:00 p.m.	Highlights from the 2008 STN Patent Forum
7/10	9:00-10:00 a.m.	Highlights from the 2008 STN Patent Forum (rebroadcast)
7/29	1:00-2:00 p.m.	Revealing the Mysteries of MARPAT®
8/14	9:00-10:00 a.m.	Revealing the Mysteries of MARPAT (rebroadcast)
8/26	1:00-2:00 p.m.	Finding Licensing Information on STN
9/11	9:00-10:00 a.m.	Finding Licensing Information on STN (rebroadcast)
9/30	1:00-2:00 p.m.	Sequence Motif Searching
10/9	9:00-10:00 a.m.	Sequence Motif Searching (rebroadcast)
10/28	1:00-2:00 p.m.	What's New in STN Express®?
11/13	9:00-10:00 a.m.	What's New in STN Express? (rebroadcast)
11/25	1:00-2:00 p.m.	Polymers in Scientific Literature
12/11	9:00-10:00 a.m.	Polymers in Scientific Literature (rebroadcast)
12/16	1:00-2:00 p.m.	Dealing with Large Answer Sets
1/8	9:00-10:00 a.m.	Dealing with Large Answer Sets (rebroadcast)

All times are U.S. Eastern Time.

For a description or to register, visit
<https://casevents.webex.com/>.

For a complete list of previously recorded e-Seminars and tutorials, select
STN e-Seminars > Recorded e-Seminars.

Topics include:

- STN AnaVist
- STN Express
- Patent Searching
- Structure Techniques
- and more

2008 FIZ Karlsruhe e-Seminar

1/17 9:00-10:00 a.m.

Searching DWPI Chemistry Resource (DCR)

Time is U.S. Eastern Time.

For descriptions or to register, visit:

www.stn-international.de/training_center/e_sem/e_desc.html



CAS Customer Care:

Phone: 800-753-4227
(North America)

614-447-3700
(worldwide)

FAX: 614-447-3751

E-mail: help@cas.org

CAS web site: www.cas.org

In This Issue

Feature

STN AnaVist, Version 2.0 – Powerful analysis and visualization software, now better than ever!.....2

Database News

BEILSTEIN, CA/CAPLUS, EMBASE, EMBAL, LEMBASE, FORIS.....6

ICSD, INPADOCDB, LINPADOCDB, REGISTRY, WPIX7

Power Up

(T) – The other proximity operator.....8

STN AnaVist Avenue

Performing comparative analysis with Version 2.011

Take Note

2007 – Year in review14

Now is the time to upgrade to STN Express, Version 8.2.....16

Order your STN Database Catalog16

Derwent Indian patent publication number format enhanced17

STNews binders available18

STNewslines – did you sign up?18

2008 CAS Trade Shows.....18

STN Seminars

2008 CAS e-Seminars.....19

2008 FIZ Karlsruhe e-Seminar19

Included with this issue

STNews: An index to the 2007 issues, STN Database Catalog postcard

In case you missed it:

STNews 2007 – Issue 2

- STN – Information solutions for drug discovery and development
- Identifying chiral drug candidates
- DWPI – Using proximity operators to design effective search strategies
- INPADOCDB – The enhanced INPADOC database
- STN Viewer – A new workflow productivity tool for patent information users
- STN Express software now free to all STN users

STNews 2007 – Issue 3

- STN Viewer – A powerful workflow productivity tool for patent information users
- USGENE and USPATOLD now available on STN
- Using the Company Name Thesaurus to track mergers and acquisitions in the pharmaceutical industry
- STN Viewer – Using the highlighting feature to speed the patent evaluation process
- STN AnaVist, Version 2.0, now available with Derwent World Patents Index

You can find it easily by searching the CAS web site at www.cas.org.

In North America

CAS
STN North America
P.O. Box 3012
Columbus, Ohio 43210-0012 U.S.A.
CAS Customer Care:
Phone: 800-753-4227 (North America)
614-447-3700 (worldwide)
Fax: 614-447-3751
E-mail: help@cas.org
Internet: www.cas.org

In Europe

FIZ Karlsruhe
STN Europe
P.O. Box 2465
76012 Karlsruhe
Germany
Phone: +49-7247-808-555
Fax: +49-7247-808-259
E-mail: helpdesk@fiz-karlsruhe.de
Internet: www.stn-international.de

In Japan

JAICI (Japan Association for International
Chemical Information)
STN Japan
Nakai Building
6-25-4 Honkomagome, Bunkyo-ku
Tokyo 113-0021, Japan
Phone: +81-3-5978-3601 (Technical Service)
+81-3-5978-3621 (Customer Service)
Fax: +81-3-5978-3600
E-mail: support@jaici.or.jp (Technical Service)
customer@jaici.or.jp (Customer Service)
Internet: www.jaici.or.jp



A division of the American Chemical Society.